

**Notice of References Cited**

Application/Control No.

10/773,113

Applicant(s)/Patent Under  
Reexamination  
DAVID, BAKER

Examiner

Mary C. Jacob

Art Unit

2123

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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